

| | | | | |
|-----------------------------------|--|---|---|-------------|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination GAN ET AL. | |
| | | Examiner <i>KP</i> Kamran Afshar, 571-272-7796 | Art Unit 2681 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-2003/0078042 A1 | 04-2003 | Miriyala et al. | 455/435 |
| | B | US-2005/0101297 A1 | 05-2005 | Delaney et al. | 455/403 |
| | C | US-6,144,857 | 11-2000 | Price et al. | 455/445 |
| | D | US-6,360,096 B1 | 03-2002 | Charpentier et al. | 455/433 |
| | E | US-5,873,101 | 02-1999 | Klein, Jonathan D. | 707/201 |
| | F | US-5,953,622 | 09-1999 | Lee et al. | 438/458 |
| | G | US-6,115,463 | 09-2000 | Coulombe et al. | 379/219 |
| | H | US-2003/0004947 A1 | 01-2003 | Coverston, Harriet G. | 707/9 |
| | I | US-5,623,532 | 04-1997 | Houde et al. | 455/445 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.